



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Haltec Corporation
122 Industry Street
Leetonia, OH 44431

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 07 August 2024

Certificate Number: AC-2896



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Haltec Corporation

122 Industry Street
Leetonia, OH 44431
Craig Andrews
330-222-1501

CALIBRATION

Valid to: **August 7, 2024**

Certificate Number: **AC-2896**

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Pressure	Up to 30 psi	0.023 psi	Fluke Digital Pressure Gages
	(30 to 60) psi	0.24 psi	
	(60 to 145) psi	0.24 psi	
	(145 to 300) psi	0.24 psi	
Torque Tools	(10 to 100) lbf·in	0.26 lbf·in	BMS Transducers
	(5 to 50) lbf·ft	0.25 lbf·ft	
	(10 to 100) lbf·ft	0.37 lbf·ft	
	(75 to 250) lbf·ft	0.77 lbf·ft	
	(40 to 400) lbf·ft	1.2 lbf·ft	
	(75 to 750) lbf·ft	2.2 lbf·ft	

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-2896.



R. Douglas Leonard Jr., VP, PILR SBU